


TRANSMITTAL

Electronic Version v1.1

Stylesheet Version v1.1.0


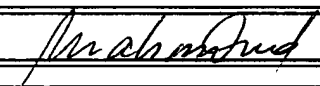
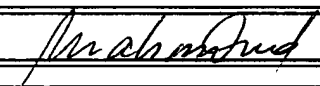
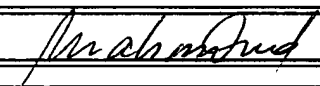
Title of Invention	METHOD FOR CONTROLLING A PROCESS FOR FABRICATING INTEGRATED DEVICES									
Application Number: 10/805136 										
Date: 2004-03-19										
First Named Applicant: Matthew F Davis										
Confirmation Number: 8916										
Attorney Docket Number: 8381/ETCH										
<p>I hereby certify that the use of this system is for OFFICIAL correspondence between patent applicants or their representatives and the USPTO. Fraudulent or other use besides the filing of official correspondence by authorized parties is strictly prohibited, and subject to a fine and/or imprisonment under applicable law.</p> <p>I, the undersigned, certify that I have viewed a display of document(s) being electronically submitted to the United States Patent and Trademark Office, using either the USPTO provided style sheet or software, and that this is the document(s) I intend for initiation or further prosecution of a patent application noted in the submission. This document(s) will become part of the official electronic record at the USPTO.</p>										
<table border="1"><thead><tr><th>Submitted by:</th><th>Elec. Sign.</th><th>Sign. Capacity</th></tr></thead><tbody><tr><td>Keith P Taboada Registered Number: 45150</td><td>/Keith P Taboada/</td><td>Attorney</td></tr></tbody></table>			Submitted by:	Elec. Sign.	Sign. Capacity	Keith P Taboada Registered Number: 45150	/Keith P Taboada/	Attorney		
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<table><tr><td>Documents being submitted</td><td>Files</td></tr><tr><td>us-ids</td><td>APPM8381-usidst.xml</td></tr><tr><td></td><td>us-ids.dtd</td></tr><tr><td></td><td>us-ids.xsl</td></tr></table>			Documents being submitted	Files	us-ids	APPM8381-usidst.xml		us-ids.dtd		us-ids.xsl
Documents being submitted	Files									
us-ids	APPM8381-usidst.xml									
	us-ids.dtd									
	us-ids.xsl									
Comments <i>final</i> <i>2/2/06</i>										



ELECTRONIC INFORMATION DISCLOSURE STATEMENT

Electronic Version v18

Stylesheet Version v18.0

Title of Invention	METHOD FOR CONTROLLING A PROCESS FOR FABRICATING INTEGRATED DEVICES																				
<p>Application Number: 10/805136 </p> <p>Confirmation Number: 8916</p> <p>First Named Applicant: Matthew Davis</p> <p>Attorney Docket Number: 8381/ETCH</p> <p>Search string: (6566025).pn.</p> <p>US Patent Documents</p> <p>Note: Applicant is not required to submit a paper copy of cited US Patent Documents</p> <table border="1"><thead><tr><th>init</th><th>Cite.No.</th><th>Patent No.</th><th>Date</th><th>Patentee</th><th>Kind</th><th>Class</th><th>Subclass</th></tr></thead><tbody><tr><td></td><td>1</td><td>6566025</td><td>2003-05-20</td><td>McStravick et al.</td><td>B1</td><td></td><td></td></tr></tbody></table> <p>Signature</p> <table border="1"><thead><tr><th>Examiner Name</th><th>Date</th></tr></thead><tbody><tr><td></td><td>2/2/06</td></tr></tbody></table>		init	Cite.No.	Patent No.	Date	Patentee	Kind	Class	Subclass		1	6566025	2003-05-20	McStravick et al.	B1			Examiner Name	Date		2/2/06
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	1	6566025	2003-05-20	McStravick et al.	B1																
Examiner Name	Date																				
	2/2/06																				

U.S. Department of Commerce, Patent and Trademark Office (PTO Form 1449 modified)					Docket No. 8381/ETCH/SILICON/JB1		Serial No. 10/805,136	
INFORMATION DISCLOSURE STATEMENT BY APPLICANT					Applicant Davis, et al.		Confirmation No.: 8916	
(Use several sheets if necessary)					Filing Date March 19, 2004		Group	
Examiner								

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U.S. Patent Documents							
*Examiner Initial		Document Number	Issue Date	Applicant(s) Name	Class	Subclass	Filing Date If Appropriate
<i>jun</i>	A1	4,767,496	08/30/1988	Hieber	156	627	
<i>jun</i>	A2	5,798,529	08/25/1998	Wagner	250	492.2	
<i>jun</i>	A3	5,926,690	07/20/1999	Toprac et al.	438	17	
<i>jun</i>	A4	5,948,203	09/07/1999	Wang	156	345	
<i>jun</i>	A5	6,004,706	12/21/1999	Ausschnitt et al.	430	30	
<i>jun</i>	A6	6,027,842	02/22/2000	Ausschnitt et al.	430	30	
<i>jun</i>	A7	6,161,054	12/12/2000	Rosenthal et al.	700	121	
<i>jun</i>	A8	6,245,581	06/12/2001	Bonser et al.	438	8	
<i>jun</i>	A9	6,424,417	07/23/2002	Cohen et al.	356	388	
<i>jun</i>	A10	6,486,492	11/26/2002	Su	257	48	
<i>jun</i>	A11	2002/0171828	11/21/2002	Cohen et al.	356	328	07/01/2002

Foreign Patent Documents								
*Examiner Initial		Document Number	Date	Country	Class	Subclass	Translation	
							YES	NO
	B1						<input type="checkbox"/>	<input type="checkbox"/>
	B2						<input type="checkbox"/>	<input type="checkbox"/>

OTHER ART	
*Examiner Initial	Including Author, Title, Date, Pertinent Pages, Etc.
<i>jun</i>	C1 Lee, et al., "Analysis of Reflectometry and Ellipsometry Data from Patterned Structures," Characterization and Metrology for UCSI Technology: 1998 International Conference, Seiler, et al., eds., pg 331-335
<i>jun</i>	C2 Raymond, "Angle-resolved scatterometry for semiconductor manufacture," Micro lithography World, Winter 2000.
<i>jun</i>	C3 Toprac, A., "AMD's Advanced Process Control of Poly-Gate Critical Dimension," Proc. SPIE Vol 3882, pg 62-65, Sept, 1999.
<i>jun</i>	C4 Yang, et al., "Line-profile and Critical Dimension Measurements Using a Normal Incidence Optical Metrology System," Proceedings of SPIE Vol. 4689, March 2002,

Examiner <i>jun</i>	Date Considered <i>2/2/05</i>
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*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with your communication to applicant.